



# SLOVENSKI STANDARD SIST EN IEC 62878-2-5:2021

01-junij-2021

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**Substrat z vdelanimi elementi - 2-5. del: Uvajanje 3D podatkovnega formata za substrat z vdelanimi elementi**

Device embedded substrate - Part 2-5: Implementation of a 3D data format for device embedded substrate

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Ta slovenski standard je istoveten z: ~~SIST EN IEC 62878-2-5:2021~~ **EN IEC 62878-2-5:2019**  
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**ICS:**

31.180	Tiskana vezja (TIV) in tiskane plošče	Printed circuits and boards
31.190	Sestavljeni elektronski elementi	Electronic component assemblies

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EUROPEAN STANDARD

**EN IEC 62878-2-5**

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November 2019

ICS 31.180; 31.190

English Version

Device embedding assembly technology - Part 2-5: Guidelines -  
Implementation of a 3D data format for device embedded  
substrate  
(IEC 62878-2-5:2019)

Techniques d'assemblage avec intégration d'appareils -  
Partie 2-5 : Lignes directrices - Mise en œuvre d'un format  
de données 3D pour un substrat avec appareils intégrés  
(IEC 62878-2-5:2019)

Montageverfahren für eingebettete Bauteile - Teil 2-5:  
Implementierung eines 3D-Datenformats für Trägermaterial  
mit eingebetteten Bauteilen  
(IEC 62878-2-5:2019)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels**

**EN IEC 62878-2-5:2019 (E)****European foreword**

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IEC 62878-2-5

Edition 1.0 2019-09

# INTERNATIONAL STANDARD



**Device embedding assembly technology –  
Part 2-5: Guidelines – Implementation of a 3D data format for device embedded  
substrate**

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

## DEVICE EMBEDDING ASSEMBLY TECHNOLOGY –

**Part 2-5: Guidelines – Implementation of a 3D data format  
for device embedded substrate**

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International Standard IEC 62878-2-5 has been prepared by IEC technical committee 91: Electronics assembly technology.

This first edition cancels and replaces IEC PAS 62878-2-5 published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the title has been changed to "Implementation of a 3D data format for device embedded substrate" from "Requirements of design data format for device embedded substrate";
- b) the scope of this implementation has changed to not include SiPs.

The text of this International Standard is based on the following documents:

CDV	Report on voting
91/1557/CDV	91/1589/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62878 series, published under the general title *Device embedding assembly technology*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

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- withdrawn,
- replaced by a revised edition, or
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## DEVICE EMBEDDING ASSEMBLY TECHNOLOGY –

### Part 2-5: Guidelines – Implementation of a 3D data format for device embedded substrate

#### 1 Scope

This part of IEC 62878 specifies requirements based on XML schema that represents a design data format for device embedded substrate, which is a board comprising embedded active and passive devices whose electrical connections are made by means of a via, electroplating, conductive paste or printing of conductive material.

This data format is to be used for simulation (e.g. stress, thermal, EMC), tooling, manufacturing, assembly, and inspection requirements. Furthermore, the data format is used for transferring information among printed board designers, printed board simulation engineer, manufacturers, and assemblers.

This part of IEC 62878 applies to substrates using organic material. It neither applies to the re-distribution layer (RDL) nor to the electronic modules defined as M-type business model in IEC 62421.

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#### 2 Normative references (standards.iteh.ai)

There are no normative references in this document.

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#### 3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

##### 3.1

##### artwork information

information that shows a SiP not included in net and figure data in board (symbol mark, inside of SiP, mould, spacer, remarks, etc.)

##### 3.2

##### board information

total information of a device-embedded substrate, including embedded devices

##### 3.3

##### chip stack

package of semiconductor chips stacked vertically

##### 3.4

##### clearance

area around a through-hole where there is no conductor to prevent electrical connection between a large conductor area, such as that of a power supply or a ground and a plated through-hole

**3.5****computer-aided manufacturing****CAM**

interactive use of computer systems, programs, and procedures in various phases of a manufacturing process wherein the decision-making activity rests with the human operator and a computer provides the data manipulation functions

**3.6****computer-aided design****CAD**

interactive use of computer systems, programs, and procedures in the design process wherein the decision-making activity rests with the human operator and a computer provides the data manipulation function

**3.7****DXF**

data format for AutoCAD

Note 1 to entry: AutoCAD is the trade name of a product supplied by Autodesk®. This information is given for the convenience of users of this document and does not constitute an endorsement by IEC of the product named. Equivalent products may be used if they can be shown to lead to the same results.

Note 2 to entry: It generally means a type of data format to draw figures using CAD board data.

**3.8****design document**

documentation of information necessary in circuit board design

**3.9****device arrangement information**

information that includes the position, the shape and attributes of the embedding device included in the net information

**3.10****device embedded substrate**

substrate in which an active device(s) (semiconductor device) and/or passive device(s) (e.g. resistor, capacitor) is formed using thick-film technology or by embedding it within the substrate

**3.11****FLIP chip****FC**

leadless monolithic circuit element structure that electrically and mechanically interconnects to a printed board by conductive bumps

**3.12****Gerber**

type of data format that consists of aperture selection and operation commands and dimensions in X- and Y-coordinates

Note 1 to entry: The data is generally used to direct a photo-plotter in generating photo-plotted artwork.

Note 2 to entry: Gerber is the trade name of a product supplied by Ucamco. This information is given for the convenience of users of this document and does not constitute an endorsement by IEC of the product named. Equivalent products may be used if they can be shown to lead to the same results.

**3.13****interposer**

material placed between two surfaces giving electrical insulation, redistribution of electrical connections, mechanical strength and/or controlled mechanical and thermal separation between the two surfaces

Note 1 to entry: An interposer may be used as a means for redistributing electrical connections and/or allowing for different thermal expansions between adjacent surfaces.

**3.14****land  
pad**

portion of a conductive pattern usually used for the connection and/or attachment of components

**3.15****land definition**

maintenance of a shape of specific land, pad, solder resist and others

**3.16****layer definition**

combination of physical information of shape and construction and logic information giving design and production units

**3.17****layer map**

map showing the relation between devices and the board, the devices being arranged on the board

**3.18****library**

database of design information based on a design document, to be used in board CAD

**3.19****logical layer**

layer that can be arbitrarily formed in the event that it is difficult to physically express a layer in a design

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Note 1 to entry: It is possible to relate it to a physical layer.

Note 2 to entry: It is different from the layers in a multi-layer substrate.

**3.20****micro-electro-mechanical system****MEMS**

system integrating micro-machine, mechanical elements, sensor, actuator, and electronic circuit into one module

**3.21****net information**

device pin construction and wiring pattern in this PAS

**3.22****package information**

shapes of board and devices when they have package shape patterns in this document

**3.23****PoP****package on package**

single or multiple package(s) mounted on a package of a single chip or multiple chips as single package

**3.24****physical layer**

layer consisting of a physical layer construction and structure

**3.25****port information**

information of figures and names of external terminals of a device or a substrate with terminals

**3.26****structure**

total structure of a device embedded substrate and/or surface device mounted to the substrate

**3.27****SiP****system in a package**

multi-chip package (MCP) that performs a system function

**3.28****thermal land**

heat energy may leak to outside of a land/through-hole when a device is soldered on a large pattern such as power supply or ground. A cut is often made around such a soldering point to prevent thermal dissipation

**3.29****through silicon via****TSV**

hole made in a silicon chip and filled with metal to electrically connect upper and lower side of the chip for 3D stacking package

**3.30****via definition**

via that is used as an interlayer connection, but in which there is no intention to insert a component lead or other reinforcing material

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**3.31****virtual layer**

name of the layer connecting conductor layers when a device is embedded

Note 1 to entry: It corresponds to the connection point of a device terminal specified in IEC TS 62678-2-3.

**3.32****wire bonding****WB**

micro-bonding between a die and base material, lead frame, etc.

**4 Data definition****4.1 Flow chart design of device embedded substrate**

Figure 1 shows the design flow of a device embedded substrate. The design data can be directly sent to a board manufacturing system using this format, or can be converted to CAM data and then be used in production. The data contain 3D information of coordinates and shapes of devices used. It is possible to check the status of device embedding in a board, and also make it a common knowledge in production know-how of a production line.

This file format describes the detailed 3D information of the following electronic circuit boards, including device embedded substrate and SiP (system in package), and makes it possible to use necessary information from the stage of design to the fabrication of products.

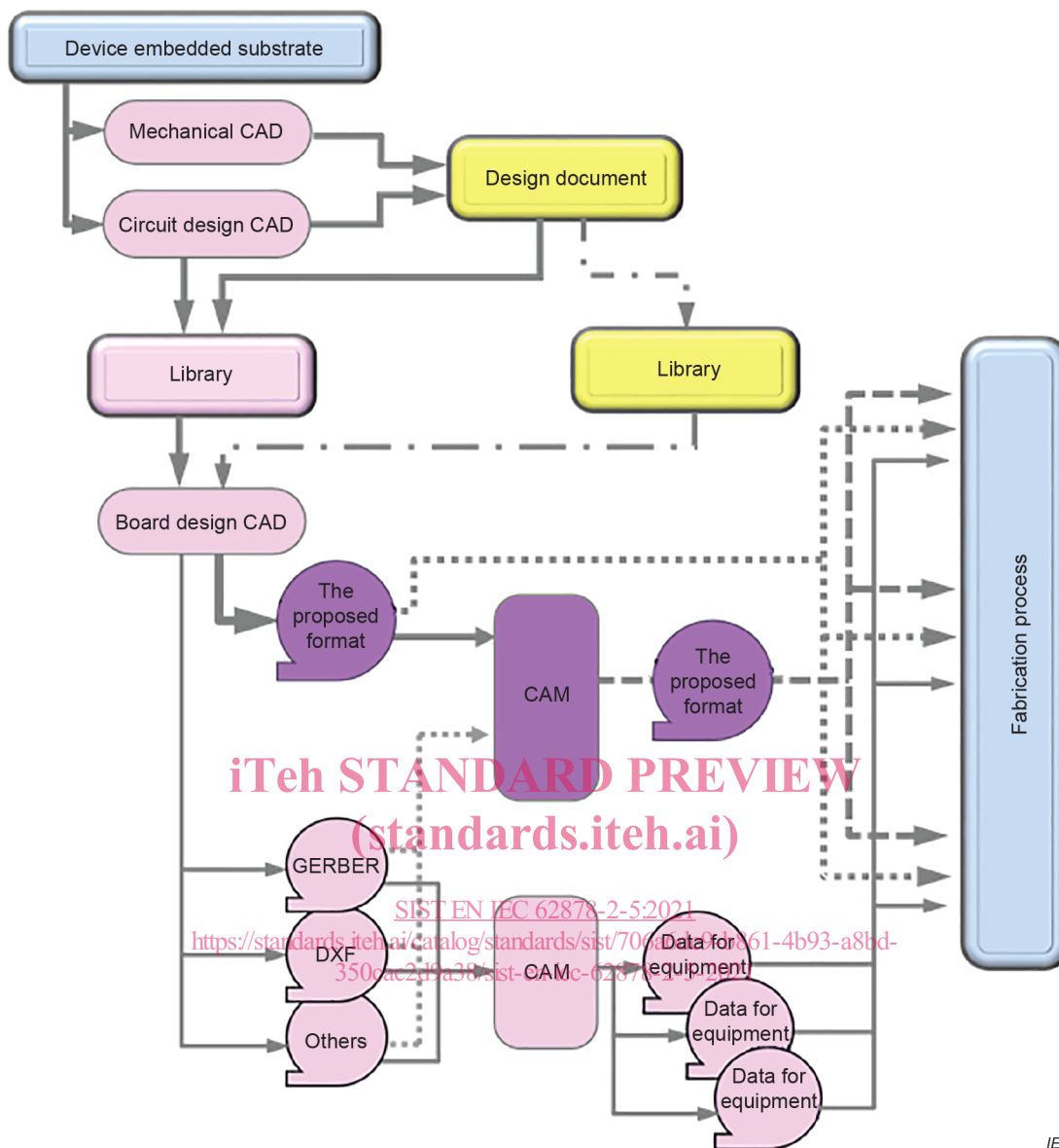


Figure 1 – Flow chart of design of device embedded substrate

## 4.2 Applicable range

### 4.2.1 Product

It is possible to maintain the following design information of a device embedded substrate as shown in Figure 2.